

TECHNICAL SPECIFICATION



**Nanomanufacturing – Key control characteristics –
Part 6-17: Graphene-based material – Order parameter: X-ray diffraction and
transmission electron microscopy**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**NANOMANUFACTURING –
KEY CONTROL CHARACTERISTICS –**
**Part 6-17: Graphene-based material –
Order parameter: X-ray diffraction and transmission electron microscopy**
FOREWORD

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Draft	Report on voting
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Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this Technical Specification is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

A list of all parts in the IEC TS 62607 series, published under the general title *Nanomanufacturing – Key control characteristics*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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INTRODUCTION

Graphite is composed of layers of carbon atoms just a single atom in thickness, known as graphene layers, to which it owes many of its remarkable properties. When the thickness of graphite flakes is reduced to just a few graphene layers, some of the material's technologically most important characteristics are greatly enhanced. In other words, graphene is more than just graphite. Although graphene has a vast number of potential applications, a survey of commercially available graphene samples reveals that research could be undermined by the poor quality of the available material [1]¹. Many highly priced graphene products from 60 producers consist mostly of graphite powder [2]. Therefore, a lack of classification standards is creating a situation that downstream users are afraid to use graphene because they do not know whether the graphene is fake.

Figure 1 shows the schematic packing configurations of graphene layers in graphite powder (left side of Figure 1) and graphene powder (right side of Figure 1) and their corresponding SEM images. It can be seen that graphite can be formed regularly in the z-axis, but graphene powder is assembled like house-of-card-type stacking, which is formed by graphene layers in a disorderly way in 3D space. For other carbon-related materials – for example, amorphous carbon, glassy carbon, expanded graphite – their packing configurations differ from those of graphite and graphene. An order parameter which indicates the order degree of a system can be employed to classify different carbon-related materials.

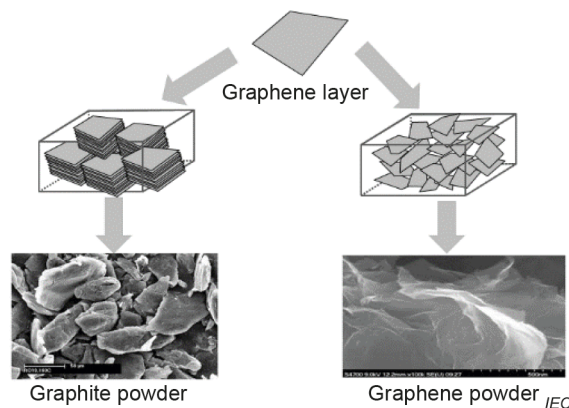


Figure 1 – Different packing configurations of graphene layers in graphite powder and graphene powder

This document establishes a method for determining the order parameter of graphene-based material and carbon material. The order parameter can be analysed from the z-axis and x-y-axis, respectively. The former can be derived from X-ray diffraction (XRD) spectra based on Bragg diffraction, and the latter can be derived from the diffraction patterns by selected area electron diffraction (SAED) technique, which is performed on a transmission electron microscope (TEM) with very high-resolution imaging. Since thermal temperature can lead to re-graphitization, the FWHM of peak (002) in the XRD spectrum indicates the quality of thermally reduced graphene powder [3]. Therefore, the order parameter can be an index of production uniformity of graphene-based materials, and also relates the materials' application with respect to heat dissipation.

¹ Numbers in square brackets refer to the Bibliography.

NANOMANUFACTURING – KEY CONTROL CHARACTERISTICS –

Part 6-17: Graphene-based material – Order parameter: X-ray diffraction and transmission electron microscopy

1 Scope

This part of IEC TS 62607 establishes a standardized method to determine the key control characteristic

- order parameter

for graphene-based material and layered carbon material by

- X-ray diffraction (XRD) and transmission electron microscopy.

The order parameter is analysed from two perspectives: z-axis and x-y-axis. In the z-axis the order parameter is derived from the full width at half maximum (FWHM) of peak (002) in the XRD spectrum. In the x-y-axis, it is derived from the FWHM of peak (100) corresponding to diffraction patterns obtained by SAED (selected area electron diffraction) technique, which is routinely performed on most transmission electron microscopes in the world.

- The method is applicable for graphene-based material and layered carbon material including graphite, expanded graphite, amorphous carbon, vitreous carbon or glassy carbon, the structures of which are clarified by other characterization techniques.
- The method is applicable for differentiating few-layer graphene or reduced graphene oxide from layered carbon material.
- Typical application area is quality control in manufacturing to ensure batch-to-batch reproducibility.

NOTE Graphene oxide, one type of graphene-based material, is not within the scope of this document.

2 Normative references

There are no normative references in this document.